

Search Notes**Application/Control No.**

10/661,503

Examiner

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Applicant(s)/Patent under Reexamination

HIKAWA ET AL.

Art Unit

2152

SEARCHED

Class	Subclass	Date	Examiner
709	224	12/16/2007	PL
717	102	12/16/2007	PL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
keywords search in 709/224, 717/102 in EAST	12/16/2007	PL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner